




<b>TEST REPORT</b> <b>IEC 62716:2013</b> <b>TÜV SÜD Test report for photovoltaic (PV) modules –</b> <b>Ammonia corrosion testing</b>	
Report reference No. ....	704061806701-00
Date of issue .....	2018-06-11
Project handler.....	Tao Wang
TÜV SÜD Branch .....	TÜV SÜD Certification and Testing (China)Co.,Ltd.Shanghai Branch
Address .....	3-13F,No.151 Heng Tong Road,200070, Shanghai, P.R.China.
Testing location .....	CuiHu Cloud Center, No.1 Gaolizhang Road, Wenquan Town, Haidian District, Beijing, China.
Client .....	Hengdian Group DMEGC Magnetics Co., LTD
Client number.....	76043
Address .....	Hengdian Industrial Zone, 322118 Dongyang City, Zhejiang Province P.R.China.
Contact person.....	Mr. Gezheng
Standard .....	This TÜV SÜD test report form is based on the following requirements: IEC 62716:2013
TRF originated by.....	Jiangsu TÜV Product Service Ltd, Shanghai Branch. Shanghai Branch, Dipl.-Ing. Alexander Krenz
Copyright blank test report .....	This test report is based on the content of the standard (see above). The test report considered selected clauses of the a.m. standard(s) and experience gained with product testing. It was prepared by TÜV SÜD Product Service GmbH.  TÜV SÜD Group takes no responsibility for and will not assume liability for damages resulting from the reader's interpretation of the reproduced material due to its placement and context.
Test procedure .....	<input type="checkbox"/> GS, <input checked="" type="checkbox"/> TÜV Mark, <input type="checkbox"/> EU-Directive, <input type="checkbox"/> without certification
Non-standard test method.....	N/A
National deviations .....	N/A
Number of pages (Report) .....	19
Number of pages (Attachments).....	3
Compiled by .... : Rongwei Jing (+ signature)	Approved by.... : Tao Wang (+ signature)

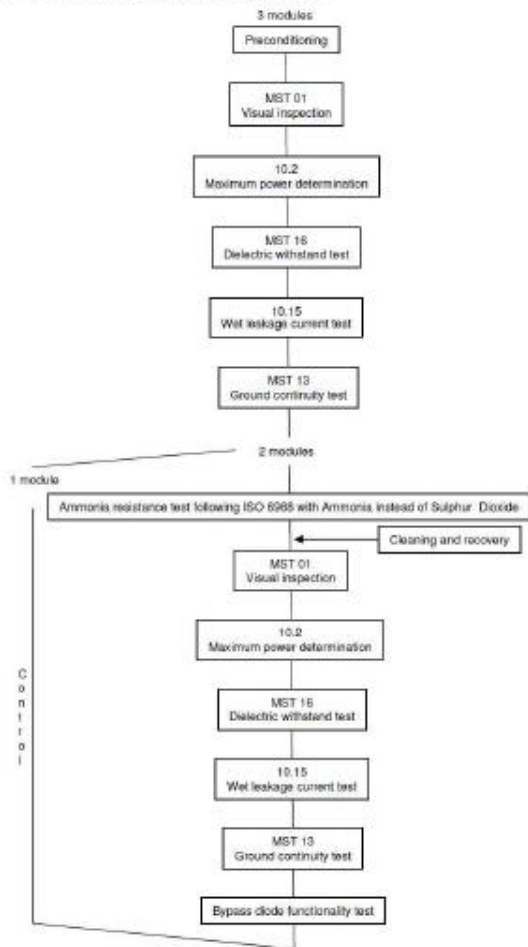


Test sample.....	1#: DMABKC60117CH00058 2#: DMABKC60117CH00049	
Type of test object .....	Mono-Crystalline Silicon Photovoltaic Module	
Trademark .....		
Model and/or type reference .....	Tested model type: DM280-M156-60BK, which can cover other models of this family as below: DMxxx-M156-72 (xxx=255-370, in step of 5W) DMxxx-M156-72BK (xxx=255-370, in step of 5W) DMxxx-M156-60 (xxx=220-305, in step of 5W) DMxxx-M156-60BK (xxx=220-305, in step of 5W) Remark: xxx is standing for rated output power at STC.	
Rating(s) .....	Rating Power at STC: 280W, application class A.	
Manufacturer .....	DMEGC SOLAR Module Factory	
Manufacturer number.....	76053	
Address .....	Hengdian Industrial Zone, 322118 Dongyang City, Zhejiang Province P.R.China.	
Sub-contractors/ tests (clause) .....	See page 4 test summary.	
Name .....	See page 4 test summary.	
Order description... ..	<input checked="" type="checkbox"/>	Complete test according to TRF
	<input type="checkbox"/>	Partial test according to manufacturer's specifications
	<input type="checkbox"/>	Preliminary test
	<input type="checkbox"/>	Spot check
Date of order.....	03/02/2018	
Date of receipt of test item .....	03/21/2018	
Date(s) of performance of test.....	03/21/2018 to 03/28/2018	

Test item particulars:

Ammonia corrosion testing of photovoltaic (PV) modules

82/600/NP



Note 1: Preconditioning and tests 10.2 and 10.15 are taken from IEC 61215. Tests MST 01, MST 13 and MST 16 are taken from IEC 61730-2.

Note 2: The control module should be used as a check every time the test modules are measured to evaluate the effect of the salt mist test.

Figure 1: Ammonia resistance test sequence for crystalline PV modules.

Attachments: photos of PV modules and laminate construction drawing.

**Summary of testing:**

**Tests performed (name of test and test clause):**

**Initial measurements:**

- Preconditioning
- MST 01: Visual inspection
- 10.2: Maximum power determination
- MST 16: Dielectric withstand test
- 10.15: Wet leakage current test
- MST 13: Ground continuity test

**Ammonia resistance test**

in accordance with ISO 6988

**Final measurements:**

- MST 01: Visual inspection
- 10.2: Maximum power determination
- MST 16: Dielectric withstand test
- 10.15: Wet leakage current test
- MST 13: Ground continuity test
- Bypass diode functionality test

**Testing location:**

Yangzhou Opto-electrical product testing institute  
 No.10 West Kaifa Road, Yangzhou, 225009  
 Jiangsu P.R.China..

**Summary of compliance with National Differences: N/A**

**Copy of marking plate:**





<b>Test item particulars</b> ..... :	
Accessories and detachable parts included in the evaluation .....	N/A
Option included .....	N/A
<b>Possible test case verdicts:</b>	
- test case does not apply to the test object..... :	N/A
- test object does meet the requirement..... :	P (Pass)
- test object does not meet the requirement .....	F (Fail)
<b>Abbreviations used in the report:</b>	
STC – Standard Test Conditions	Vmp – Maximum power voltage
Imp – Maximum power current	Voc – Open circuit voltage
Isc – Short circuit current	WL – Wet leakage current
Pmp – Maximum power	
<b>General remarks:</b>	
<p>The test results presented in this report relate only to the object tested.                      This report shall not be reproduced, except in full, without the written approval of the Issuing testing laboratory.                      "(see Enclosure #)" refers to additional information appended to the report.                      "(see appended table)" refers to a table appended to the report.</p> <p>Throughout this report a point is used as the decimal separator.                      Summary of contents provided on the last page of this report.</p>	
<b>General product information and considerations:</b>	
<b>Product Electrical Ratings:</b>	
Type or model number	DM280-M156-60BK
Voc (Vdc)	38.9
Vmp (Vdc)	31.0
Imp (Adc)	9.02
Isc (Adc)	9.55
Pmp (W)	280
Deviation of Pmp at STC or Minimum value of Pmp (for thin film module) (%)	±3%
Maximum system voltage (V)	1000V DC
Maximum over-current protection rating (A)	15A
Application Class	A



Information for testing sample:

Sample #	Type	Series number
1	DM280-M156-60BK	DMABKC60117CH00058
2	DM280-M156-60BK	DMABKC60117CH00049

**Description of module construction:  
 (Manufactories and part numbers, unless otherwise specified)**

Sample :	Random sampling from production <input checked="" type="checkbox"/> Prototype submitted by client <input type="checkbox"/>
Module	
Front Cover :	Type: Tempered glass / Coated glass Thickness: 3.2(mm) Flat glass Group Co., Ltd.
Rear Cover :	Cynagard 225A , Black, Thickness: 290 µm Max. system voltage: 1000VDC Cybrid Technologies Inc.
Encapsulation material :	Hangzhou First Photovolatiac Material Co., Ltd. F406PS/F806PS, Thickness: 0.55/0.5mm or 0.5/0.45mm
Frame:	Anodized Aluminum Alloy, 6063-T5, Jianguyin Haihong New Energy Technology Co., Ltd.
Dimensions (l x w x h) [mm] :	DMxxx-M156-72& DMxxx-M156-72BK: 1956x992x40, 1960x992x45, 1960x992x40, 1960x991x45,1960x991x40 DMxxx-M156-60& DMxxx-M156-60BK: 1650x992x40,1650x992x35
Module area [m <sup>2</sup> ] :	1.94/1.64
Adhesives (junction box) :	1527, black color. Suzhou TONSAN Adhesive., Ltd.
Minimum distance between current-carrying parts and module edge [mm]	DMxxx-M156-72& DMxxx-M156-72BK: 15mm DMxxx-M156-60& DMxxx-M156-60BK: 15mm
<b>Cell</b>	



Cell (include type) .....	DMTD5B157-210, Mono-si,156.75x156.75mm, Thickness : 200±20µm, 5 bus-bars Front surface:0.7mm silver busbar Back surface:1.4mm silver discontinuous soldering pads Hengdian Group DMEGC Magnetcs Co.,Ltd.
Cells (l x w) [mm] .....	156.75x156.75
Cell thickness [µm].....	200±20µm
Cell area [cm <sup>2</sup> ] .....	244.32
Number of cells.....	72/60
<b>Components</b>	
Cells per bypass diode :	24/20
Type of bypass diode :	Type: PST4020 Schottky Max. peak reverse voltage 45V Forward Rectified current 30A Max junction temperature 200°C Zhejiang Rehen Photovoltaic Technology Co., Ltd.
No. of bypass diodes :	3
Cell- and string connectors:	0.25x0.9 mm, Sn60%Pb40% Suzhou Yourbest New-type Materials Co.,Ltd. 0.45x6.0 mm, Sn60%Pb40% Suzhou Yourbest New-type Materials Co., Ltd.
Junction box :	GF20XY, rated voltage 1500V DC, rated input current 15A, IP68, 40°C~+85°C, Application class A. Zhejiang Rehen Photovoltaic Technology Co., Ltd.
Cable :	H1Z2Z2-K, 1x4 mm <sup>2</sup> , 1500VDC, -40 to +90°C Zhejiang Rehen Photovoltaic Technology Co., Ltd.
Connectors :	05-6 , Rated voltage 1000V DC,Rated current 20A, Application class A, IP67, -40°C~85°C. Zhejiang Rehen Photovoltaic Technology Co., Ltd.
Adhesives (frame) :	1527, black color. Tonsan Adhesive,Inc.
Potting material (junction box) :	1521, black color. Tonsan Adhesive,Inc.
<b>Receiver</b>	
Type :	N/A
Dimension (l x w x h) [mm] :	N/A
Front Cover :	N/A
Rear Cover :	N/A
Encapsulation material :	N/A
<b>Mirror</b>	
Type :	N/A
Dimension (l x w) [mm] :	N/A
Other	Fluxing agent Type: SF56, Wuxi Asahi Solder Co., Ltd.
Others:	Insulation material between busbar: EPE 3M



IEC 62716:2013			
Clause	Requirement + Test	Result--Remark	Verdict
<b>3</b>	<b>Samples</b>		P
	– Three identical samples of the model of PV module or assembly of interest must be subjected to any of the testing sequences included in Figures 1, 2, or 3, depending on the PV technology considered, namely crystalline silicon, thin-film or concentrator photovoltaic (CPV) respectively.	Three samples evaluated	P
	– Full-size sample or representative sample	Full Size Samples	P
	– PV module provided with means for grounding then they constitute a part of the test sample.	With Grounding devices.	P
<b>4</b>	<b>Test procedures</b>		P
4.1	– All tests included in Figures 1, 2 or 3, except the bypass diode functionality test, are fully described in the IEC standards.		P
4.2	Bypass Diode Functionality Test		P
<b>5</b>	<b>Preconditioning</b>		P
	– All test samples must be preconditioned with either global or direct normal sunlight according to the specifications given in the applicable Design Qualification and Type Approval IEC standard applicable.	Performed according to IEC 61215:2005.	P
<b>6</b>	<b>Initial Measurements</b>		P
6.1	Crystalline silicon		P
	– Tests according to IEC 61215		P
	a) 10.2: Maximum power determination	See table 6-b)	P
	b) 10.15: Wet leakage current test	See table 6-d)	P
	– Tests according to IEC 61730-2		P
	c) MST 01: Visual inspection	See table 6-a)	P
	d) MST 13: Ground continuity test	See table 6-e)	P
	e) MST 16: Dielectric withstand test	See table 6-c)	P
6.2	Thin-film technologies		N/A
	– Tests according to IEC 61646		N/A
	a) 10.2: Maximum power determination	See table 6-b)	N/A
	b) 10.15: Wet leakage current test	See table 6-d)	N/A
	– Tests according to IEC 61730-2		N/A
	c) MST 01: Visual inspection	See table 6-a)	N/A

Test Report based on IEC 62716:2013 Rev. 00





IEC 62716:2013			
Clause	Requirement + Test	Result--Remark	Verdict
	d) MST 13: Ground continuity test	See table 6-e)	N/A
	e) MST 16: Dielectric withstand test	See table 6-c)	N/A
<b>7</b>	<b>Ammonia resistance test</b>		P
<b>7.1</b>	Testing facility and material		-
	As described in section 3 of ISO 6988	See table 7	P
<b>7.2</b>	Test condition and execution	See table 7.	P
	– specimen position: the inclination to the vertical of the face of the module normally exposed to solar irradiance shall be 15° to 30° inside the climatic chambers.	Inclination of 30°C.	P
<b>8</b>	<b>Cleaning and recovery</b>		P
	– After the ammonia test all samples must be washed to remove the adherent salt using running tap water for a maximum time of 5 minutes per square meter of area of the sample.		P
	– The temperature of the water used for washing shall not exceed 35 °C.		P
	– During cleaning or drying the use of cloths, gauzes or any other woven material shall be avoided and no scraping is allowed		P
<b>9</b>	<b>Final Measurements</b>		P
	After the ammonia test the test samples shall be subjected to the following tests depending on the PV module technology.		-
<b>9.1</b>	Crystalline silicon		-
	– Tests according to IEC 61215		-
	a) 10.2: Maximum power determination	See table 9-b)	P
	b) 10.15: Wet leakage current test	See table 9-d)	P
	– Tests according to IEC 61730-2		-
	c) MST 01: Visual inspection	See table 9-a)	P
	d) MST 13: Ground continuity test	See table 9-e)	P
	e) MST 16: Dielectric withstand test	See table 9-c)	P



IEC 62716:2013			
Clause	Requirement + Test	Result--Remark	Verdict
	– Tests according to this standard:		P
	f) Bypass diode functionality test	See table 9-g)	P
9.2	Thin-film technologies	Tested modules are mono Crystalline silicon.	N/A
	– Tests according to IEC 61646		N/A
	a) 10.2: Maximum power determination at STC after light soaking	See table 9-b)	N/A
	b) 10.15: Wet leakage current test	See table 9-d)	N/A
	c) 10.19: light soaking	See table 9-f)	N/A
	– Tests according to IEC 61730-2		N/A
	d) MST 01: Visual inspection	See table 9-a)	N/A
	e) MST 13: Ground continuity test	See table 9-e)	N/A
	f) MST 16: Dielectric withstand test	See table 9-c)	N/A
	– Tests according to this standard:		N/A
	g) Bypass diode functionality test	See table 9-g)	N/A

<b>10</b>	<b>Requirements</b>		P
<b>10.1</b>	Crystalline silicon		P
	– After the ammonia test, no evidence of major visual defects as described in IEC 61730-2.	See table 9-a)	P
	– After the ammonia test the maximum power shall not decrease by more than 5% of the initial value.	See table 9-b)	P
	– All pass fail criteria corresponding to tests 10.15, MST 13 and MST 16 must be fulfilled.	MST16 see table 9-c) 10.15 see table 9-d) MST13 see table 9-e)	P
	– The requirement for the bypass diode functionality test must be also fulfilled.	See table 9-g)	P
<b>10.2</b>	Thin-film technologies		N/A
	– After the ammonia test, no evidence of major visual defects as described in IEC 61730-2.	See table 9-a)	N/A
	– After the light soaking the maximum power at STC shall not be less than 90% of the minimum value specified by the manufacturer in the marking of the PV module.	See table 9-b)	N/A



IEC 62716:2013			
Clause	Requirement + Test	Result--Remark	Verdict
	– All pass fail criteria corresponding to tests 10.15, 10.19, MST 13 and MST 16 must be fulfilled.	MST16 see table 9-c) 10.15 see table 9-d) MST13 see table 9-e) 10.19 see table 9-f)	N/A
	– The requirement for the bypass diode functionality test must be also fulfilled.	See table 9-g)	N/A



<b>6-a)</b>	<b>TABLE: Visual inspection (Initial)</b>		P
Test Date [MM/DD/YYYY].....:		03/21/2018	—
Sample No.	Nature and position of initial findings – comments or attach photos		Verdict
1#	No major visual defects		P
2#	No major visual defects		P
Supplementary information:-			

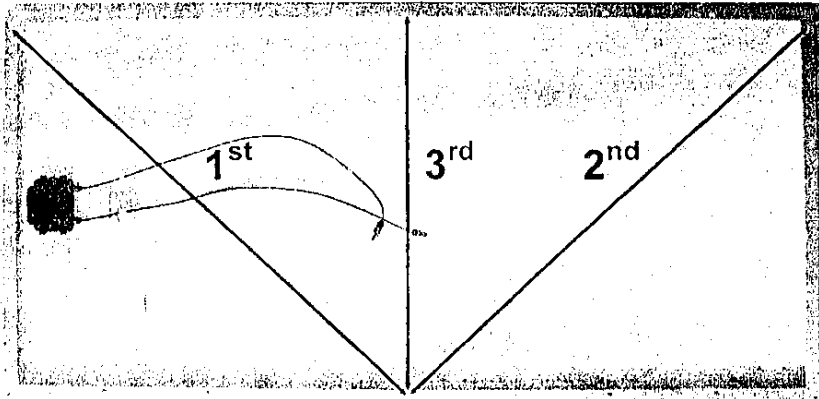
<b>6-b)</b>	<b>TABLE: I-V characteristic (Initial)</b>					P
Test Date [MM/DD/YYYY].....:		03/21/2018			—	
Radiant Source.....:		<input checked="" type="checkbox"/> Solar simulator		<input type="checkbox"/> Natural Sunlight		
Module temperature [°C] .....		25			—	
Irradiance [W/m <sup>2</sup> ] .....		1000			—	
Sample No.	Voc [V]	Vmp [V]	Isc [A]	Imp [A]	Pmp [W]	FF[%]
1#	38.779	31.801	9.235	8.994	283.134	79.06
2#	38.772	31.775	9.281	9.014	283.977	78.92
Supplementary information: -						

<b>6-c)</b>	<b>Table: Insulation test (initial)</b>				P
Test Date [YYYY-MM-DD] .....		03/21/2018			—
Test Voltage applied [V] .....		6000/1000			—
Sample #	Measured	Required	Dielectric breakdown		Result
	MΩ	MΩ	Yes (description)	No	
1#	>5000	24.39	No dielectric breakdown	x	P
2#	>5000	24.39	No dielectric breakdown	x	P
Supplementary information: Size of module [m <sup>2</sup> ]: 1.64. The maximum resistance measurement range is 5000 MΩ					

<b>6-d)</b>	<b>TABLE: Wet leakage current test (Initial)</b>			P
Test Date [MM/DD/YYYY].....:		03/21/2018		—
Test voltage applied [V] .....		1000		—
Module maximum system voltage rating (V, DC) .....		1000		—
Solution resistivity [Ω cm], < 3,500 Ω cm at 22 ± 3 °C .....		2714 at 22.5°C.		—
Sample No.	Measured [MΩ]		Limit [MΩ]	Result
1#	374.3		24.39	P
2#	419.5		24.39	P
Supplementary information: Size of module [m <sup>2</sup> ]: 1.64.				

<b>6-e)</b>	<b>MST 13 – ground continuity test (Initial)</b>			P
	Maximum over-current protection rating (A)	03/21/2018	—	
	Current applied (A) .....	15	P	
	Location of designated grounding point.....	37.5	—	
	Location of second contacting point.....	Grounding point of the long edge	—	
Sample No.	Position in test sequence:	Voltage (V)	Resistance ( $\Omega$ )	Result
1#	Initial examination	0.1875/0.1875/0.1500	0.005/0.005/0.004	P
2#	Initial examination	0.1125/0.1500/0.1875	0.003/0.004/0.005	P

Supplementary information:  
 The wire connection during test is shown as the following figure:



<b>7</b>	<b>TABLE: Ammonia resistance test procedure</b>			P
20 Cycles	1 test section	Hours including heating up	8 hours	—
		NH3 – Concentration (ppm)	(6667±50)ppm	—
		Temperature (°C)	60±3	—
		Rel. Humidity (%)	100%,bedewing samples	—
	2 test section	Hours including cooling	16 hours	—
		NH3 – Concentration (ppm)	0ppm	—
		Temperature (°C)	23±5°C	—
		Rel. Humidity max (%)	75% relative humidity	—
Duration (cycle, hours).....:		20 cycles(480hs)	—	
Supplementary information: -				



<b>9-a)</b>	<b>TABLE: Visual inspection (final)</b>		P
Test Date [MM/DD/YYYY].....:		05/28/2018	—
Sample No.	Nature and position of initial findings – comments or attach photos		Verdict
1#	No defects		P
2#	No defects		P
Supplementary information: -			

<b>9-b)</b>	<b>TABLE: Maximum power determination (final)</b>							P
Test Date [MM/DD/YYYY] start-end .....		05/28/2018					—	
Module temperature [°C] low-high .....		25					—	
Irradiance [W/m <sup>2</sup> ] low-high .....		1000					—	
Sample #	Voc [V]	Vmp [V]	Isc [A]	Imp [A]	FF [%]	Pmp [W]	Degradation [%]	Limit [%]
1#	38.601	31.836	9.308	8.880	78.68	282.704	-0.15	-5
2#	38.450	31.136	9.263	8.852	78.62	280.027	-1.39	-5
Supplementary information:								
Crystalline silicon module: Pmp degradation after this test ≤ 5%								
Thin film module: minimum value of Pmp at STC after this test ≥ 90% of minimum value of marking								

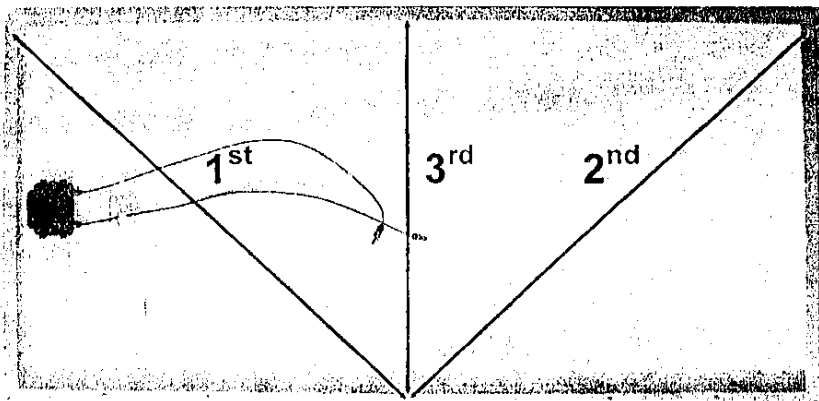
<b>9-c)</b>	<b>Table: Insulation test (final)</b>				P
Test Date [YYYY-MM-DD].....:		05/28/2017			—
Test Voltage applied [V] .....		6000/1000			—
Sample #	Measured	Required	Dielectric breakdown		Result
	MΩ	MΩ	Yes (description)	No	
1#	>5000	24.39	No dielectric breakdown		x P
2#	>5000	24.39	No dielectric breakdown		x P
Supplementary information: Size of module [m <sup>2</sup> ]: 1.64. The maximum resistance measurement range is 5000 MΩ					

<b>9-d)</b>	<b>TABLE: Wet leakage current test (final)</b>			P
Test Date [MM/DD/YYYY].....:		05/28/2018		—
Test voltage applied [V] .....		1000		—
Module maximum system voltage rating (V, DC).....:		1000		—
Solution resistivity [Ω cm], < 3,500 Ω cm at 22 ± 3 °C .....		2704at 22.4°C		—
Sample No.	Measured [MΩ]		Limit [MΩ]	Verdict

2#	282.3	24.39	P
3#	747.9	24.39	P
Supplementary information: Size of module [m <sup>2</sup> ]: 1.94			

<b>9-e)</b>	<b>MST 13 – ground continuity test</b>			P
	Maximum over-current protection rating (A)	15		—
	Current applied (A) .....	37.5		—
	Location of designated grounding point.....	Refer to supplementary info.		—
	Location of second contacting point.....	Refer to supplementary info.		—
Sample No.	Position in test sequence:	Volatge (V)	Resistance (Ω)	Result
#1	Final examination	0.1875/0.1500/0.1500	0.005/0.004/0.004	P
#2	Final examination	0.2625/0.2250/0.1500	0.007/0.006/0.004	P

Supplementary information:  
The wire connection during test is shown as the following figure:



<b>9-f)</b>	<b>TABLE: Light soaking</b>						N/A	
Abbreviation: Regarding light source “S” for Solar simulator and “N” for Natural sunlight								
Sample #	Test Date (MM/DD/YYYY) start/end							
Test cycle	Light source	Irradiance applied (kWh/m <sup>2</sup> )	Average irradiance (W/m <sup>2</sup> )	Module temperature during test (°C)			Pmp(W) at the end of cycle	Change in Pmp in the cycle (%)
				min	max	avg		
Initial	—	—	—	—	—	—		—
								N/A
								N/A
Supplementary information:								
Sample #	Test Date (MM/DD/YYYY) start/end							
Test cycle	Light source	Irradiance applied	Average irradiance	Module temperature during test (°C)			Pmp(W) at the end of	Change in Pmp in the
				min	max	avg		



		(kWh/m2)	(W/m2)				cycle	cycle (%)
Initial	—	—	—	—	—	—		—
								N/A
								N/A
Supplementary information:								

9-g)	TABLE: Bypass diode thermal test						P
Sample No.	#1						—
Test Date [MM/DD/YYYY].....:	05/28/2018						—
Module temperature [°C]..... :	25.0						—
Number of diodes in junction box..... :	3						—
Diode manufacturer .....	Zhejiang Rehen Photovoltaic Technology Co.,Ltd.						—
Diode type designation .....	Type: PST4020,Schottky						—
Rated STC short-circuit current [A]..... :	9.204						—
Current flow (1.25 * Isc) [A] .....	11.5						P
Test duration (hour)	1						P
	D1	D2	D3				Result
Diode functional? yes/no .....	yes	yes	yes				P
Sample No.	#2						—
Test Date [MM/DD/YYYY].....:	05/28/2018						—
Module temperature [°C]..... :	25.0						—
Number of diodes in junction box..... :	3						—
Diode manufacturer .....	Zhejiang Rehen Photovoltaic Technology Co.,Ltd.						—
Diode type designation .....	Type: PST4020,Schottky						—
Rated STC short-circuit current [A]..... :	9.297						—
Current flow (1.25 * Isc) [A] .....	11.6						P
Test duration (hour)	1						P
	D1	D2	D3				Result
Diode functional? yes/no .....	yes	yes	yes				P





### Annex 1: List of measurement equipment

Description	Model	Equipment ID	Effective date of calibration
Magnifying lamp	F-500	SB08111	June-20-2017/ June-19-2018
Steel tape	5m	SB08102	May -03-2017/ May -02-2018
Ruler	30cm	SB08108	April -29-2017/ April -28-2018
Light Meter	731	SB08125	April -26-2017/ April -25-2018
Electrical Safety compliance Analyzer	7142	SB10018	May -26-2017/ May -25-2018
Pulsed Solar Simulator	PSS-30	SB08001	April -07-2018/ April -06-2019
Ground continuity tester	7316	SB08047	May-22-2017/ May-21-2018
Wet leakage current tester	Custom	SB08079	April-10-2018/ April-09-2019
NH3 chamber	NH3-400	SB13010	April-10-2018/ April-09-2019

### Annex 2: Statement of the estimated uncertainty of the test results

Statement of the estimated uncertainty of the I/V test, K=2.

$$U(P_{\max})=2.6\%$$

**Annex 3: Photos of samples**





-- END OF REPORT